J Mater Sci: Mater Electron (2021) 32:14119–14120

Correction

Correction to: Annealing temperature-driven near-surface crystallization with improved luminescence in self-patterned alumina films

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Published online:
26 April 2021

Correction to:
Journal of Materials Science: Materials in Electronics
https://doi.org/10.1007/s10854-021-05790-0

Unfortunately, in the original version of this article the updated Fig. 3 was not replaced. Please find below the updated Fig. 3. This has been corrected by publishing this correction article.

The original article has been updated.

The original article can be found online at https://doi.org/10.1007/s10854-021-05790-0.

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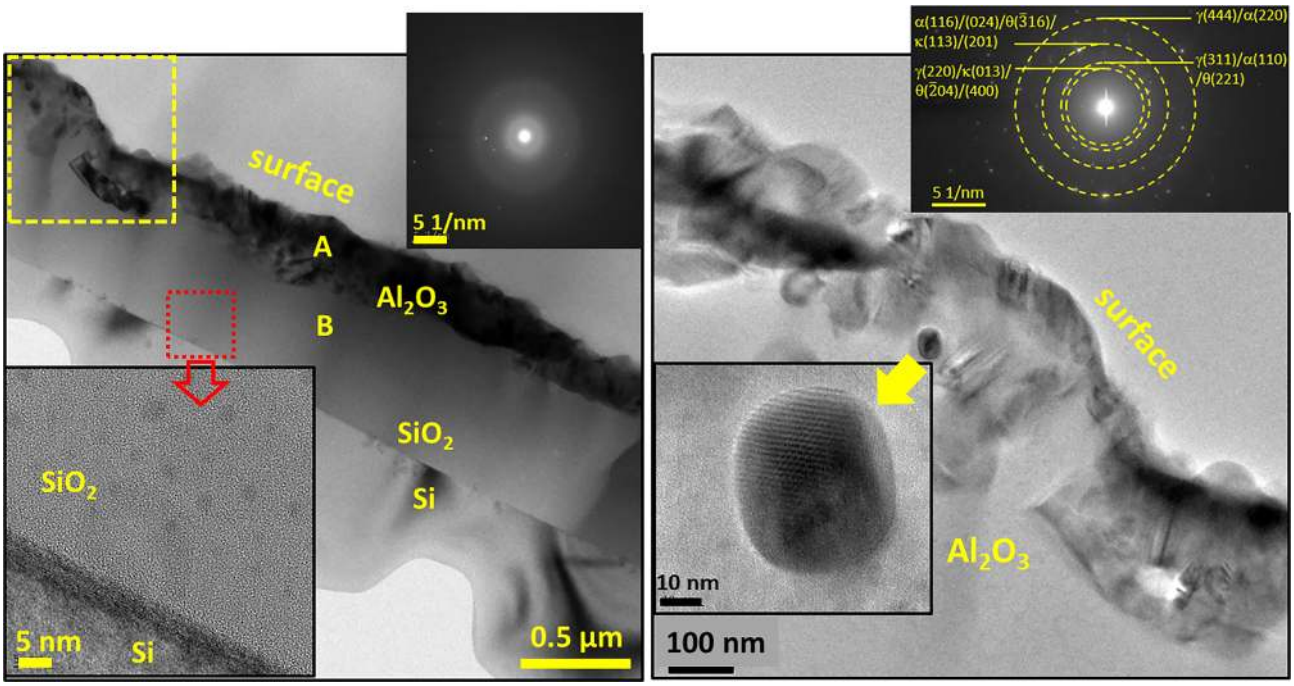

Fig. 3 Left panel displays low magnification bright-field XTEM image of A-1200. The SAED pattern corresponding to region B (top right corner inset) depicts diffuse rings, indicating an amorphous phase. The HRTEM image of the SiO_2/Si junction reveals a sharp interface (bottom left inset). Right panel exhibits a magnified image of the surface region (highlighted by a yellow box in left panel). The layer is crystalline and contains precipitates, one of which is further magnified in the image shown at the bottom. The SAED pattern originating from the surface crystalline layer is shown in the top right inset. The yellow circles indicating the main interplanar distances expected from the various phases of alumina lying on the observed diffraction spots (Color figure online)